# IAP20 Rec'd FCT/F10 03 FEB 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Ken Iizuka Appl. No.: Unknown Conf. No.: Unknown

Filed: February 3, 2006

Title: IMAGE MATCHING METHOD, IMAGE MATCHING APPARATUS, AND

PROGRAM Unknown

Art Unit: Unknown Examiner: Unknown Docket No. 112857-672

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

### INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 37 C.F.R. 1.97, and 37 C.F.R. 1.98, Applicants request that a citation and examination of the references cited below, and on the attached PTO-1449 form be made during the course of examination of the above-identified application for United States patent. Pursuant to 37 C.F.R. 1.98, copies of all foreign patent documents and non-patent documents are enclosed.

#### FOREIGN PATENT DOCUMENTS

Document No.	<u>Date</u>	Country
10-021391	01-23-1998	Japan
10-162139	06-19-1998	Japan
11-003421	01-06-1999	Japan

Applicants look forward to early and favorable consideration of this matter.

Respectfully submitted,
BY
Thomas C. Basso (46,541)
Cust. No. 29175

Dated: February 3, 2006

AP20 Rec'd PCT/PTO 0 3 FEB 2006
Docket No. 17987,672 | 107/587,182

#### INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)

PTO Form 1449

		U.S. PATE	NT DOCUMENT	S		
Examiner's Initials	Document Number	Publication Date	Inventor	Class	Subclass	Filing Date If Appropriate
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			PATENT DOCUME	NTS			
Examiner's	Document	Publication				Trans	
Initials	Number	Date	Country	Class	Subclass	Yes	No
/A.W./	10-021391	01-23-1998	Japan				
/A.W./	10-162139	06-19-1998	Japan				
/A.W./	11-003421	01-06-1999	Japan				
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Examiner's Initials	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
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Examiner:	/Akililu Woldemariam/	Date Considered: 10/15	2009
*Examiner:	Initial if citation considered, whether or no	t citation is in conformance	with MPEP Section 609;
Draw line t	hrough citation if not in conformance and	not considered. Include con	ov of this form with next

communication to applicant.